

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/589,382	OGATA ET AL.	
Examiner	Art Unit	
Sin J. Lee	1795	

	SEARCHED				
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EIC structure search for formula (2) compound (to be scanned soon).	10/24/2008	SJL		